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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	64
Number of Logic Elements/Cells	256
Total RAM Bits	-
Number of I/O	81
Number of Gates	3000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-BQFP
Supplier Device Package	100-PQFP (20x14)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc5202-6pq100c

XC5200 Family Compared to XC4000/Spartan™ and XC3000 Series

For readers already familiar with the XC4000/Spartan and XC3000 FPGA Families, this section describes significant differences between them and the XC5200 family. Unless otherwise indicated, comparisons refer to both XC4000/Spartan and XC3000 devices.

Configurable Logic Block (CLB) Resources

Each XC5200 CLB contains four independent 4-input function generators and four registers, which are configured as four independent Logic Cells™ (LCs). The registers in each XC5200 LC are optionally configurable as edge-triggered D-type flip-flops or as transparent level-sensitive latches.

The XC5200 CLB includes dedicated carry logic that provides fast arithmetic carry capability. The dedicated carry logic may also be used to cascade function generators for implementing wide arithmetic functions.

XC4000 family: XC5200 devices have no wide edge decoders. Wide decoders are implemented using cascade logic. Although sacrificing speed for some designs, lack of wide edge decoders reduces the die area and hence cost of the XC5200.

XC4000/Spartan family: XC5200 dedicated carry logic differs from that of the XC4000/Spartan family in that the sum is generated in an additional function generator in the adjacent column. This design reduces XC5200 die size and hence cost for many applications. Note, however, that a loadable up/down counter requires the same number of function generators in both families. XC3000 has no dedicated carry.

XC4000/Spartan family: XC5200 lookup tables are optimized for cost and hence cannot implement RAM.

Input/Output Block (IOB) Resources

The XC5200 family maintains footprint compatibility with the XC4000 family, but not with the XC3000 family.

To minimize cost and maximize the number of I/O per Logic Cell, the XC5200 I/O does not include flip-flops or latches.

For high performance paths, the XC5200 family provides direct connections from each IOB to the registers in the adjacent CLB in order to emulate IOB registers.

Each XC5200 I/O Pin provides a programmable delay element to control input set-up time. This element can be used to avoid potential hold-time problems. Each XC5200 I/O Pin is capable of 8-mA source and sink currents.

IEEE 1149.1-type boundary scan is supported in each XC5200 I/O.

Table 2: Xilinx Field-Programmable Gate Array Families

Parameter	XC5200	Spartan	XC4000	XC3000
CLB function generators	4	3	3	2
CLB inputs	20	9	9	5
CLB outputs	12	4	4	2
Global buffers	4	8	8	2
User RAM	no	yes	yes	no
Edge decoders	no	no	yes	no
Cascade chain	yes	no	no	no
Fast carry logic	yes	yes	yes	no
Internal 3-state	yes	yes	yes	yes
Boundary scan	yes	yes	yes	no
Slew-rate control	yes	yes	yes	yes

Routing Resources

The XC5200 family provides a flexible coupling of logic and local routing resources called the VersaBlock. The XC5200 VersaBlock element includes the CLB, a Local Interconnect Matrix (LIM), and direct connects to neighboring VersaBlocks.

The XC5200 provides four global buffers for clocking or high-fanout control signals. Each buffer may be sourced by means of its dedicated pad or from any internal source.

Each XC5200 TBUF can drive up to two horizontal and two vertical Longlines. There are no internal pull-ups for XC5200 Longlines.

Configuration and Readback

The XC5200 supports a new configuration mode called Express mode.

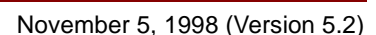
XC4000/Spartan family: The XC5200 family provides a global reset but not a global set.

XC5200 devices use a different configuration process than that of the XC3000 family, but use the same process as the XC4000 and Spartan families.

XC3000 family: Although their configuration processes differ, XC5200 devices may be used in daisy chains with XC3000 devices.

XC3000 family: The XC5200 PROGRAM pin is a single-function input pin that overrides all other inputs. The PROGRAM pin does not exist in XC3000.

The GRM is functionally similar to the switch matrices found in other architectures, but it is novel in its tight coupling to the logic resources contained in the VersaBlocks. Advanced simulation tools were used during the development of the XC5200 architecture to determine the optimal level of routing resources required. The XC5200 family contains six levels of interconnect hierarchy — a series of



single-length lines, double-length lines, and Longlines all routed through the GRM. The direct connects, LIM, and logic-cell feedthrough are contained within each Versa-Block. Throughout the XC5200 interconnect, an efficient multiplexing scheme, in combination with three layer metal (TLM), was used to improve the overall efficiency of silicon usage.

Performance Overview

The XC5200 family has been benchmarked with many designs running synchronous clock rates beyond 66 MHz. The performance of any design depends on the circuit to be implemented, and the delay through the combinatorial and sequential logic elements, plus the delay in the interconnect routing. A rough estimate of timing can be made by assuming 3-6 ns per logic level, which includes direct-connect routing delays, depending on speed grade. More accurate estimations can be made using the information in the Switching Characteristic Guideline section.

Taking Advantage of Reconfiguration

FPGA devices can be reconfigured to change logic function while resident in the system. This capability gives the system designer a new degree of freedom not available with any other type of logic.

Hardware can be changed as easily as software. Design updates or modifications are easy, and can be made to products already in the field. An FPGA can even be reconfigured dynamically to perform different functions at different times.

Reconfigurable logic can be used to implement system self-diagnostics, create systems capable of being reconfigured for different environments or operations, or implement multi-purpose hardware for a given application. As an added benefit, using reconfigurable FPGA devices simplifies hardware design and debugging and shortens product time-to-market.

Detailed Functional Description

Configurable Logic Blocks (CLBs)

Figure 4 shows the logic in the XC5200 CLB, which consists of four Logic Cells (LC[3:0]). Each Logic Cell consists of an independent 4-input Lookup Table (LUT), and a D-Type flip-flop or latch with common clock, clock enable, and clear, but individually selectable clock polarity. Additional logic features provided in the CLB are:

- An independent 5-input LUT by combining two 4-input LUTs.
- High-speed carry propagate logic.
- High-speed pattern decoding.
- High-speed direct connection to flip-flop D-inputs.
- Individual selection of either a transparent, level-sensitive latch or a D flip-flop.
- Four 3-state buffers with a shared Output Enable.

5-Input Functions

Figure 5 illustrates how the outputs from the LUTs from LC0 and LC1 can be combined with a 2:1 multiplexer (F5_MUX) to provide a 5-input function. The outputs from the LUTs of LC2 and LC3 can be similarly combined.

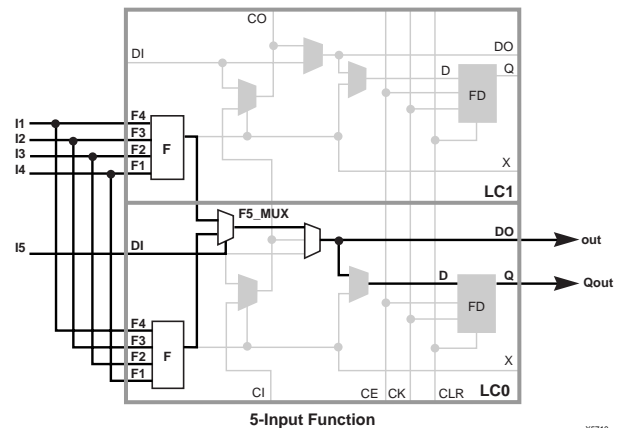



Figure 5: Two LUTs in Parallel Combined to Create a 5-input Function

Table 3: CLB Storage Element Functionality (active rising edge is shown)

Mode	CK	CE	CLR	D	Q
Power-Up or GR	X	X	X	X	0
Flip-Flop	X	X	1	X	0
	—/	1*	0*	D	D
	0	X	0*	X	Q
Latch	1	1*	0*	X	Q
	0	1*	0*	D	D
Both	X	0	0*	X	Q

X	Don't care
	Rising edge
0*	Input is Low or unconnected (default value)
1*	Input is High or unconnected (default value)

The source of a storage element data input is programmable. It is driven by the function F, or by the Direct In (DI) block input. The flip-flops or latches drive the Q CLB outputs.

The four edge-triggered D-type flip-flops or level-sensitive latches have common clock (CK) and clock enable (CE) inputs. Any of the clock inputs can also be permanently enabled. Storage element functionality is described in [Table 3](#).

The flip-flops can be triggered on either the rising or falling clock edge. The clock pin is shared by all four storage elements with individual polarity control. Any inverter placed on the clock input is automatically absorbed into the CLB.

The clock enable signal (CE) is active High. The CE pin is shared by the four storage elements. If left unconnected for any, the clock enable for that storage element defaults to the active state. CE is not invertible within the CLB.

An asynchronous storage element input (CLR) can be used to reset all four flip-flops or latches in the CLB. This input

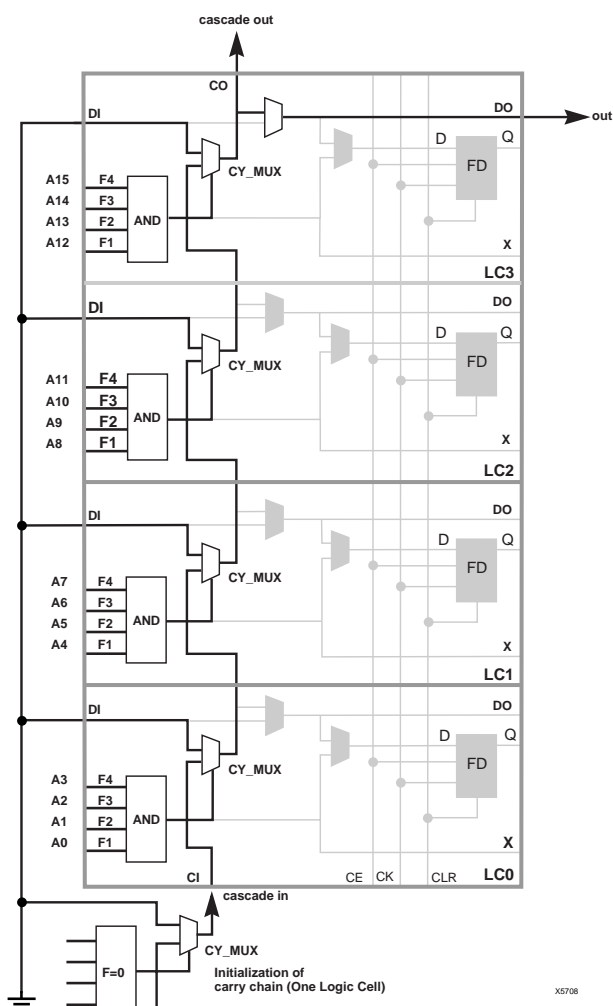


Figure 7: XC5200 CY_MUX Used for Decoder Cascade Logic

Each CY_MUX can be connected to the CY_MUX in the adjacent LC to provide cascadable decode logic. **Figure 7** illustrates how the 4-input function generators can be configured to take advantage of these four cascaded CY_MUXes. Note that AND and OR cascading are specific cases of a general decode. In AND cascading all bits are decoded equal to logic one, while in OR cascading all bits are decoded equal to logic zero. The flexibility of the LUT achieves this result. The XC5200 library contains gate macros designed to take advantage of this function.

The CLB can pass the combinatorial output(s) to the interconnect network, but can also store the combinatorial

VersaRing Input/Output Interface

The VersaRing, shown in **Figure 18**, is positioned between the core logic and the pad ring; it has all the routing resources of a VersaBlock without the CLB logic. The VersaRing decouples the core logic from the I/O pads. Each VersaRing Cell provides up to four pad-cell connections on one side, and connects directly to the CLB ports on the other side.

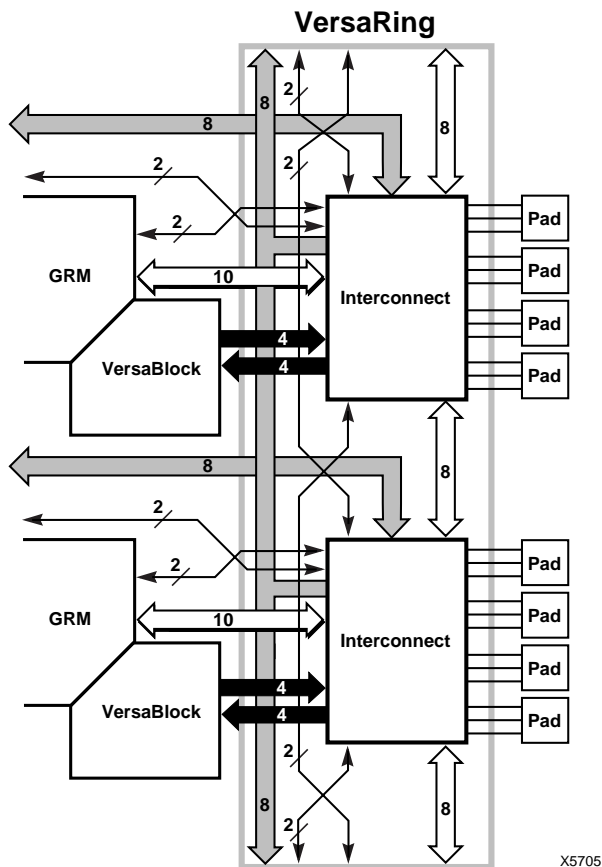


Figure 18: VersaRing I/O Interface

Boundary Scan

The “bed of nails” has been the traditional method of testing electronic assemblies. This approach has become less appropriate, due to closer pin spacing and more sophisticated assembly methods like surface-mount technology and multi-layer boards. The IEEE boundary scan standard 1149.1 was developed to facilitate board-level testing of electronic assemblies. Design and test engineers can imbed a standard test logic structure in their device to achieve high fault coverage for I/O and internal logic. This structure is easily implemented with a four-pin interface on any boundary scan-compatible IC. IEEE 1149.1-compatible devices may be serial daisy-chained together, connected in parallel, or a combination of the two.

XC5200 devices support all the mandatory boundary-scan instructions specified in the IEEE standard 1149.1. A Test Access Port (TAP) and registers are provided that implement the EXTEST, SAMPLE/PRELOAD, and BYPASS instructions. The TAP can also support two USERCODE instructions. When the boundary scan configuration option is selected, three normal user I/O pins become dedicated inputs for these functions. Another user output pin becomes the dedicated boundary scan output.

Boundary-scan operation is independent of individual IOB configuration and package type. All IOBs are treated as independently controlled bidirectional pins, including any unbonded IOBs. Retaining the bidirectional test capability after configuration provides flexibility for interconnect testing.

Also, internal signals can be captured during EXTEST by connecting them to unbonded IOBs, or to the unused outputs in IOBs used as unidirectional input pins. This technique partially compensates for the lack of INTEST support.

The user can serially load commands and data into these devices to control the driving of their outputs and to examine their inputs. This method is an improvement over bed-of-nails testing. It avoids the need to over-drive device outputs, and it reduces the user interface to four pins. An optional fifth pin, a reset for the control logic, is described in the standard but is not implemented in Xilinx devices.

The dedicated on-chip logic implementing the IEEE 1149.1 functions includes a 16-state machine, an instruction register and a number of data registers. The functional details can be found in the IEEE 1149.1 specification and are also discussed in the Xilinx application note XAPP 017: “Boundary Scan in XC4000 and XC5200 Series devices”

Figure 19 on page 99 is a diagram of the XC5200-Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

The public boundary-scan instructions are always available prior to configuration. After configuration, the public instructions and any USERCODE instructions are only available if specified in the design. While SAMPLE and BYPASS are available during configuration, it is recommended that boundary-scan operations not be performed during this transitory period.

In addition to the test instructions outlined above, the boundary-scan circuitry can be used to configure the FPGA device, and to read back the configuration data.

All of the XC4000 boundary-scan modes are supported in the XC5200 family. Three additional outputs for the User-Register are provided (Reset, Update, and Shift), repre-

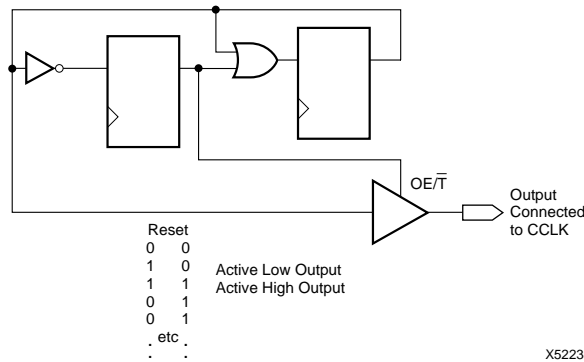


Figure 22: CCLK Generation for XC3000 Master Driving an XC5200-Series Slave

Express Mode

Express mode is similar to Slave Serial mode, except the data is presented in parallel format, and is clocked into the target device a byte at a time rather than a bit at a time. The data is loaded in parallel into eight different columns: it is not internally serialized. Eight bits of configuration data are loaded with every CCLK cycle, therefore this configuration mode runs at eight times the data rate of the other six modes. In this mode the XC5200 family is capable of supporting a CCLK frequency of 10 MHz, which is equivalent to an 80 MHz serial rate, because eight bits of configuration data are being loaded per CCLK cycle. An XC5210 in the Express mode, for instance, can be configured in about 2 ms. The Express mode does not support CRC error checking, but does support constant-field error checking. A length count is not used in Express mode.

In the Express configuration mode, an external signal drives the CCLK input(s). The first byte of parallel configuration data must be available at the D inputs of the FPGA devices a short set-up time before the second rising CCLK edge. Subsequent data bytes are clocked in on each consecutive rising CCLK edge. See [Figure 38 on page 123](#).

Bitstream generation currently generates a bitstream sufficient to program in all configuration modes except Express. Extra CCLK cycles are necessary to complete the configuration, since in this mode data is read at a rate of eight bits per CCLK cycle instead of one bit per cycle. Normally the entire start-up sequence requires a number of bits that is equal to the number of CCLK cycles needed. An additional five CCLKs (equivalent to 40 extra bits) will guarantee completion of configuration, regardless of the start-up options chosen.

Multiple slave devices with identical configurations can be wired with parallel D0-D7 inputs. In this way, multiple devices can be configured simultaneously.

Pseudo Daisy Chain

Multiple devices with different configurations can be connected together in a pseudo daisy chain, provided that all of the devices are in Express mode. A single combined bitstream is used to configure the chain of Express mode devices, but the input data bus must drive D0-D7 of each device. Tie High the CS1 pin of the first device to be configured, or leave it floating in the XC5200 since it has an internal pull-up. Connect the DOUT pin of each FPGA to the CS1 pin of the next device in the chain. The D0-D7 inputs are wired to each device in parallel. The DONE pins are wired together, with one or more internal DONE pull-ups activated. Alternatively, a 4.7 kΩ external resistor can be used, if desired. (See [Figure 37 on page 122](#).) CCLK pins are tied together.

The requirement that all DONE pins in a daisy chain be wired together applies only to Express mode, and only if all devices in the chain are to become active simultaneously. All devices in Express mode are synchronized to the DONE pin. User I/O for each device become active after the DONE pin for that device goes High. (The exact timing is determined by options to the bitstream generation software.) Since the DONE pin is open-drain and does not drive a High value, tying the DONE pins of all devices together prevents all devices in the chain from going High until the last device in the chain has completed its configuration cycle.

The status pin DOUT is pulled LOW two internal-oscillator cycles (nominally 1 MHz) after INIT is recognized as High, and remains Low until the device's configuration memory is full. Then DOUT is pulled High to signal the next device in the chain to accept the configuration data on the D7-D0 bus. All devices receive and recognize the six bytes of preamble and length count, irrespective of the level on CS1; but subsequent frame data is accepted only when CS1 is High and the device's configuration memory is not already full.

Setting CCLK Frequency

For Master modes, CCLK can be generated in one of three frequencies. In the default slow mode, the frequency is nominally 1 MHz. In fast CCLK mode, the frequency is nominally 12 MHz. In medium CCLK mode, the frequency is nominally 6 MHz. The frequency range is -50% to +50%. The frequency is selected by an option when running the bitstream generation software. If an XC5200-Series Master is driving an XC3000- or XC2000-family slave, slow CCLK mode must be used. Slow mode is the default.

Table 11: XC5200 Bitstream Format

Data Type	Value	Occurrences
Fill Byte	11111111	Once per bitstream
Preamble	11110010	
Length Counter	COUNT(23:0)	
Fill Byte	11111111	

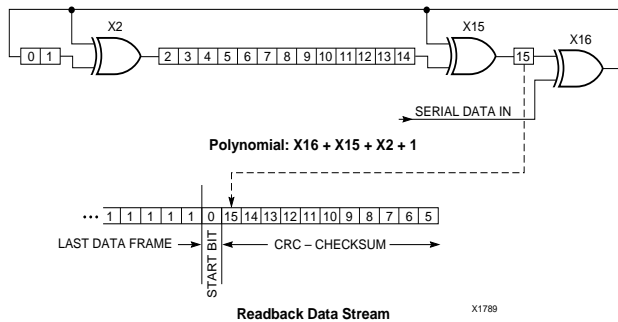


Figure 23: Circuit for Generating CRC-16

Configuration Sequence

There are four major steps in the XC5200-Series power-up configuration sequence.

- Power-On Time-Out
- Initialization
- Configuration
- Start-Up

The full process is illustrated in [Figure 24](#).

Power-On Time-Out

An internal power-on reset circuit is triggered when power is applied. When V_{CC} reaches the voltage at which portions of the FPGA begin to operate (i.e., performs a write-and-read test of a sample pair of configuration memory bits), the programmable I/O buffers are 3-stated with active high-impedance pull-up resistors. A time-out delay — nominally 4 ms — is initiated to allow the power-supply voltage to stabilize. For correct operation the power supply must reach $V_{CC}(\text{min})$ by the end of the time-out, and must not dip below it thereafter.

There is no distinction between master and slave modes with regard to the time-out delay. Instead, the INIT line is used to ensure that all daisy-chained devices have completed initialization. Since XC2000 devices do not have this signal, extra care must be taken to guarantee proper operation when daisy-chaining them with XC5200 devices. For proper operation with XC3000 devices, the RESET signal, which is used in XC3000 to delay configuration, should be connected to INIT.

If the time-out delay is insufficient, configuration should be delayed by holding the INIT pin Low until the power supply has reached operating levels.

This delay is applied only on power-up. It is not applied when reconfiguring an FPGA by pulsing the PROGRAM pin Low. During all three phases — Power-on, Initialization, and Configuration — DONE is held Low; HDC, LDC, and INIT are active; DOUT is driven; and all I/O buffers are disabled.

Initialization

This phase clears the configuration memory and establishes the configuration mode.

The configuration memory is cleared at the rate of one frame per internal clock cycle (nominally 1 MHz). An open-drain bidirectional signal, INIT, is released when the configuration memory is completely cleared. The device then tests for the absence of an external active-low level on INIT. The mode lines are sampled two internal clock cycles later (nominally 2 μs).

The master device waits an additional 32 μs to 256 μs (nominally 64-128 μs) to provide adequate time for all of the slave devices to recognize the release of INIT as well. Then the master device enters the Configuration phase.

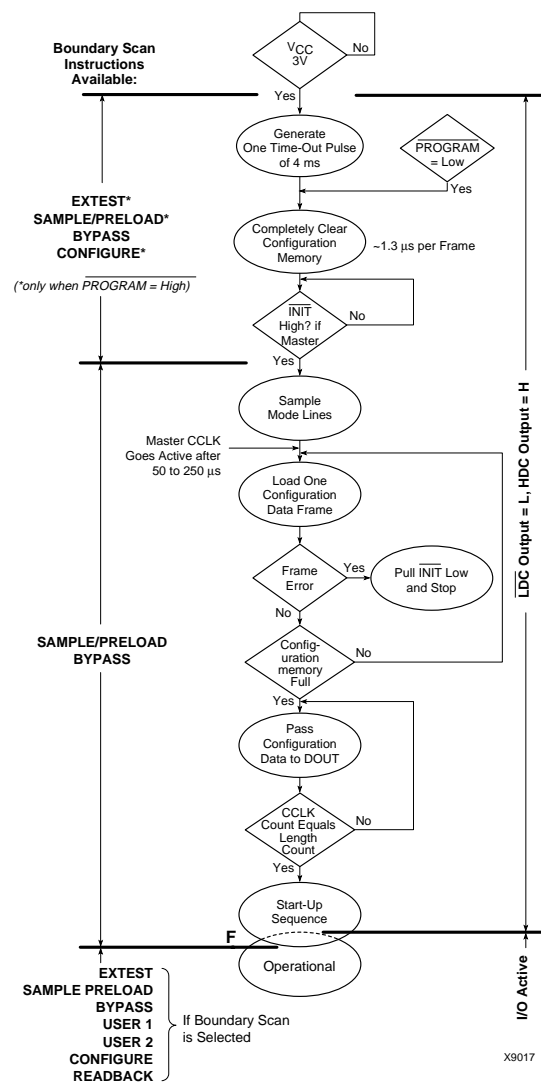


Figure 24: Configuration Sequence

Configuration

The length counter begins counting immediately upon entry into the configuration state. In slave-mode operation it is important to wait at least two cycles of the internal 1-MHz clock oscillator after $\overline{\text{INIT}}$ is recognized before toggling CCLK and feeding the serial bitstream. Configuration will not begin until the internal configuration logic reset is released, which happens two cycles after $\overline{\text{INIT}}$ goes High. A master device's configuration is delayed from 32 to 256 μs to ensure proper operation with any slave devices driven by the master device.

The 0010 preamble code, included for all modes except Express mode, indicates that the following 24 bits represent the length count. The length count is the total number of configuration clocks needed to load the complete configuration data. (Four additional configuration clocks are required to complete the configuration process, as discussed below.) After the preamble and the length count have been passed through to all devices in the daisy chain, DOUT is held High to prevent frame start bits from reaching any daisy-chained devices. In Express mode, the length count bits are ignored, and DOUT is held Low, to disable the next device in the pseudo daisy chain.

A specific configuration bit, early in the first frame of a master device, controls the configuration-clock rate and can increase it by a factor of eight. Therefore, if a fast configuration clock is selected by the bitstream, the slower clock rate is used until this configuration bit is detected.

Each frame has a start field followed by the frame-configuration data bits and a frame error field. If a frame data error is detected, the FPGA halts loading, and signals the error by pulling the open-drain $\overline{\text{INIT}}$ pin Low. After all configuration frames have been loaded into an FPGA, DOUT again follows the input data so that the remaining data is passed on to the next device. In Express mode, when the first device is fully programmed, DOUT goes High to enable the next device in the chain.

Delaying Configuration After Power-Up

To delay master mode configuration after power-up, pull the bidirectional $\overline{\text{INIT}}$ pin Low, using an open-collector (open-drain) driver. (See [Figure 12](#).)

Using an open-collector or open-drain driver to hold $\overline{\text{INIT}}$ Low before the beginning of master mode configuration causes the FPGA to wait after completing the configuration memory clear operation. When $\overline{\text{INIT}}$ is no longer held Low externally, the device determines its configuration mode by capturing its mode pins, and is ready to start the configuration process. A master device waits up to an additional 250 μs to make sure that any slaves in the optional daisy chain have seen that $\overline{\text{INIT}}$ is High.

Start-Up

Start-up is the transition from the configuration process to the intended user operation. This transition involves a change from one clock source to another, and a change from interfacing parallel or serial configuration data where most outputs are 3-stated, to normal operation with I/O pins active in the user-system. Start-up must make sure that the user-logic 'wakes up' gracefully, that the outputs become active without causing contention with the configuration signals, and that the internal flip-flops are released from the global Reset at the right time.

[Figure 25](#) describes start-up timing for the three Xilinx families in detail. Express mode configuration always uses either CCLK_SYNC or UCLK_SYNC timing, the other configuration modes can use any of the four timing sequences.

To access the internal start-up signals, place the STARTUP library symbol.

Start-up Timing

Different FPGA families have different start-up sequences.

The XC2000 family goes through a fixed sequence. DONE goes High and the internal global Reset is de-activated one CCLK period after the I/O become active.

The XC3000A family offers some flexibility. DONE can be programmed to go High one CCLK period before or after the I/O become active. Independent of DONE, the internal global Reset is de-activated one CCLK period before or after the I/O become active.

The XC4000/XC5200 Series offers additional flexibility. The three events — DONE going High, the internal Reset being de-activated, and the user I/O going active — can all occur in any arbitrary sequence. Each of them can occur one CCLK period before or after, or simultaneous with, any of the others. This relative timing is selected by means of software options in the bitstream generation software.

The default option, and the most practical one, is for DONE to go High first, disconnecting the configuration data source and avoiding any contention when the I/Os become active one clock later. Reset is then released another clock period later to make sure that user-operation starts from stable internal conditions. This is the most common sequence, shown with heavy lines in [Figure 25](#), but the designer can modify it to meet particular requirements.

Normally, the start-up sequence is controlled by the internal device oscillator output (CCLK), which is asynchronous to the system clock.

XC4000/XC5200 Series offers another start-up clocking option, UCLK_NOSYNC. The three events described above need not be triggered by CCLK. They can, as a configuration option, be triggered by a user clock. This means that the device can wake up in synchronism with the user system.

Master Serial Mode

In Master Serial mode, the CCLK output of the lead FPGA drives a Xilinx Serial PROM that feeds the FPGA DIN input. Each rising edge of the CCLK output increments the Serial PROM internal address counter. The next data bit is put on the SPROM data output, connected to the FPGA DIN pin. The lead FPGA accepts this data on the subsequent rising CCLK edge.

The lead FPGA then presents the preamble data—and all data that overflows the lead device—on its DOUT pin. There is an internal pipeline delay of 1.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

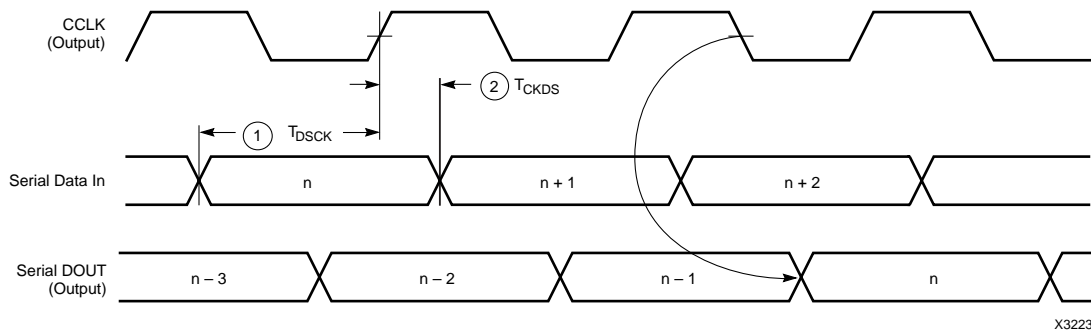
In the bitstream generation software, the user can specify Fast ConfigRate, which, starting several bits into the first frame, increases the CCLK frequency by a factor of twelve.

The value increases from a nominal 1 MHz, to a nominal 12 MHz. Be sure that the serial PROM and slaves are fast enough to support this data rate. The Medium ConfigRate option changes the frequency to a nominal 6 MHz. XC2000, XC3000/A, and XC3100A devices do not support the Fast or Medium ConfigRate options.

The SPROM \overline{CE} input can be driven from either \overline{LDC} or \overline{DONE} . Using \overline{LDC} avoids potential contention on the DIN pin, if this pin is configured as user-I/O, but \overline{LDC} is then restricted to be a permanently High user output after configuration. Using \overline{DONE} can also avoid contention on DIN, provided the \overline{DONE} before I/O enable option is invoked.

Figure 28 on page 114 shows a full master/slave system. The leftmost device is in Master Serial mode.

Master Serial mode is selected by a <000> on the mode pins (M2, M1, M0).



	Description	Symbol	Min	Max	Units
CCLK	DIN setup	1 T_{DSCK}	20		ns
	DIN hold	2 T_{CKDS}	0		ns

Notes: 1. At power-up, V_{CC} must rise from 2.0 V to V_{CC} min in less than 25 ms, otherwise delay configuration by pulling $\overline{PROGRAM}$ Low until V_{CC} is valid.
2. Master Serial mode timing is based on testing in slave mode.

Figure 30: Master Serial Mode Programming Switching Characteristics

In the two Master Parallel modes, the lead FPGA directly addresses an industry-standard byte-wide EPROM, and accepts eight data bits just before incrementing or decrementing the address outputs.

The eight data bits are serialized in the lead FPGA, which then presents the preamble data—and all data that overflows the lead device—on its DOUT pin. There is an internal delay of 1.5 CCLK periods, after the rising CCLK edge that accepts a byte of data (and also changes the EPROM address) until the falling CCLK edge that makes the LSB (D0) of this byte appear at DOUT. This means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

The PROM address pins can be incremented or decremented, depending on the mode pin settings. This option allows the FPGA to share the PROM with a wide variety of microprocessors and microcontrollers. Some processors must boot from the bottom of memory (all zeros) while others must boot from the top. The FPGA is flexible and can load its configuration bitstream from either end of the memory.

Master Parallel Up mode is selected by a <100> on the mode pins (M2, M1, M0). The EPROM addresses start at 00000 and increment.

Master Parallel Down mode is selected by a <110> on the mode pins. The EPROM addresses start at 3FFFF and decrement.

Express Mode

Express mode is similar to Slave Serial mode, except that data is processed one byte per CCLK cycle instead of one bit per CCLK cycle. An external source is used to drive CCLK, while byte-wide data is loaded directly into the configuration data shift registers. A CCLK frequency of 10 MHz is equivalent to an 80 MHz serial rate, because eight bits of configuration data are loaded per CCLK cycle. Express mode does not support CRC error checking, but does support constant-field error checking.

In Express mode, an external signal drives the CCLK input of the FPGA device. The first byte of parallel configuration data must be available at the D inputs of the FPGA a short setup time before the second rising CCLK edge. Subsequent data bytes are clocked in on each consecutive rising CCLK edge.

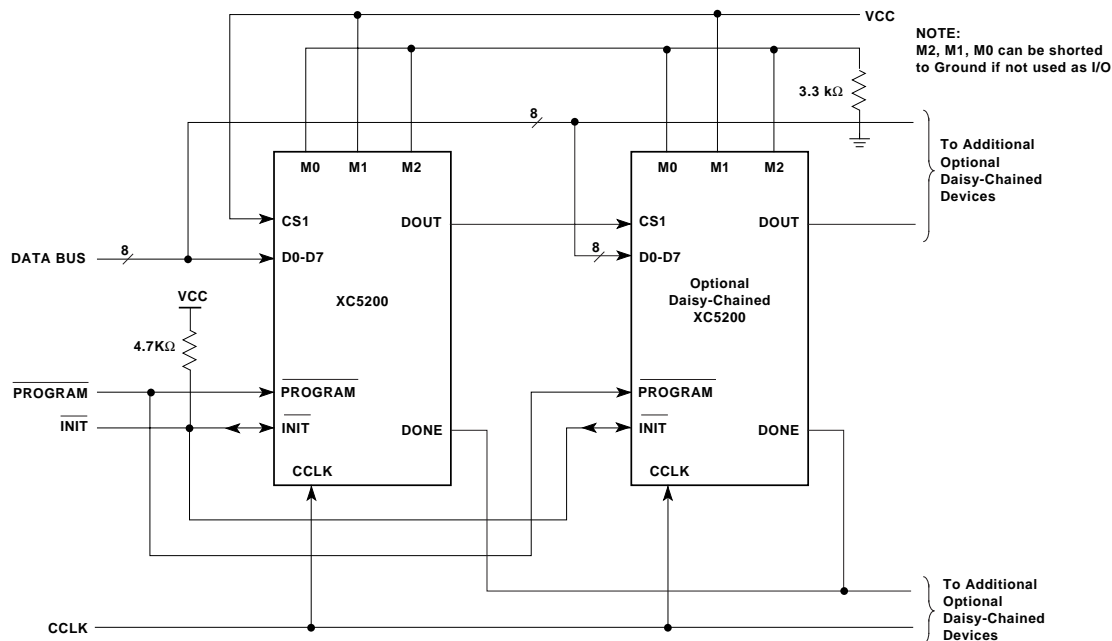
If the first device is configured in Express mode, additional devices may be daisy-chained only if every device in the chain is also configured in Express mode. CCLK pins are tied together and D0-D7 pins are tied together for all devices along the chain. A status signal is passed from DOUT to CS1 of successive devices along the chain. The lead device in the chain has its CS1 input tied High (or floating, since there is an internal pullup). Frame data is accepted only when CS1 is High and the device's configu-

ration memory is not already full. The status pin DOUT is pulled Low two internal-oscillator cycles after INIT is recognized as High, and remains Low until the device's configuration memory is full. DOUT is then pulled High to signal the next device in the chain to accept the configuration data on the D0-D7 bus.

The DONE pins of all devices in the chain should be tied together, with one or more active internal pull-ups. If a large number of devices are included in the chain, deactivate some of the internal pull-ups, since the Low-driving DONE pin of the last device in the chain must sink the current from all pull-ups in the chain. The DONE pull-up is activated by default. It can be deactivated using an option in the bitstream generation software.

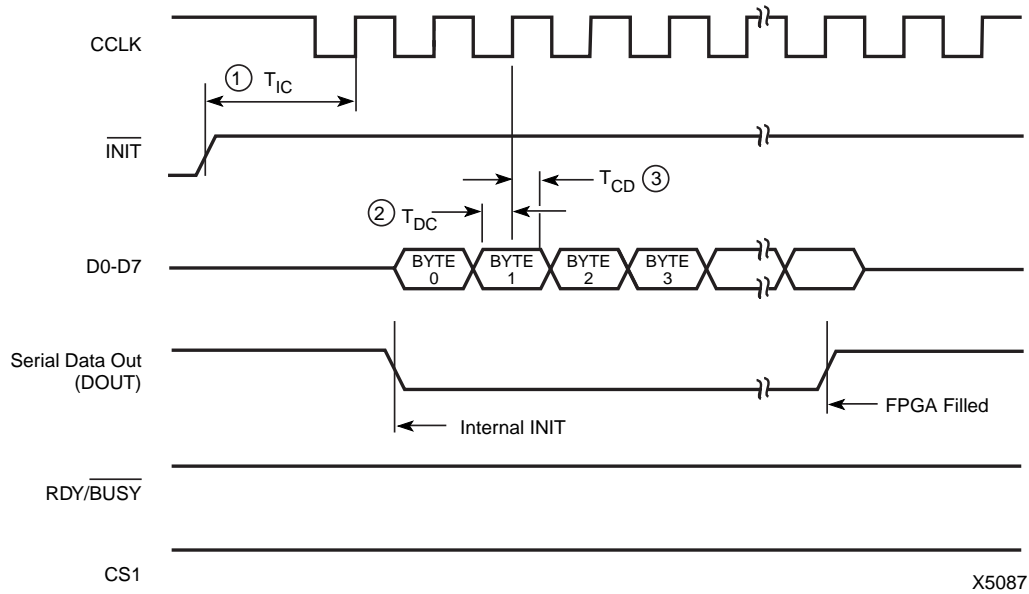
XC5200 devices in Express mode are always synchronized to DONE. The device becomes active after DONE goes High. DONE is an open-drain output. With the DONE pins tied together, therefore, the external DONE signal stays low until all devices are configured, then all devices in the daisy chain become active simultaneously. If the DONE pin of a device is left unconnected, the device becomes active as soon as that device has been configured.

Express mode is selected by a <010> on the mode pins (M2, M1, M0).



X6611_01

Figure 37: Express Mode Circuit Diagram

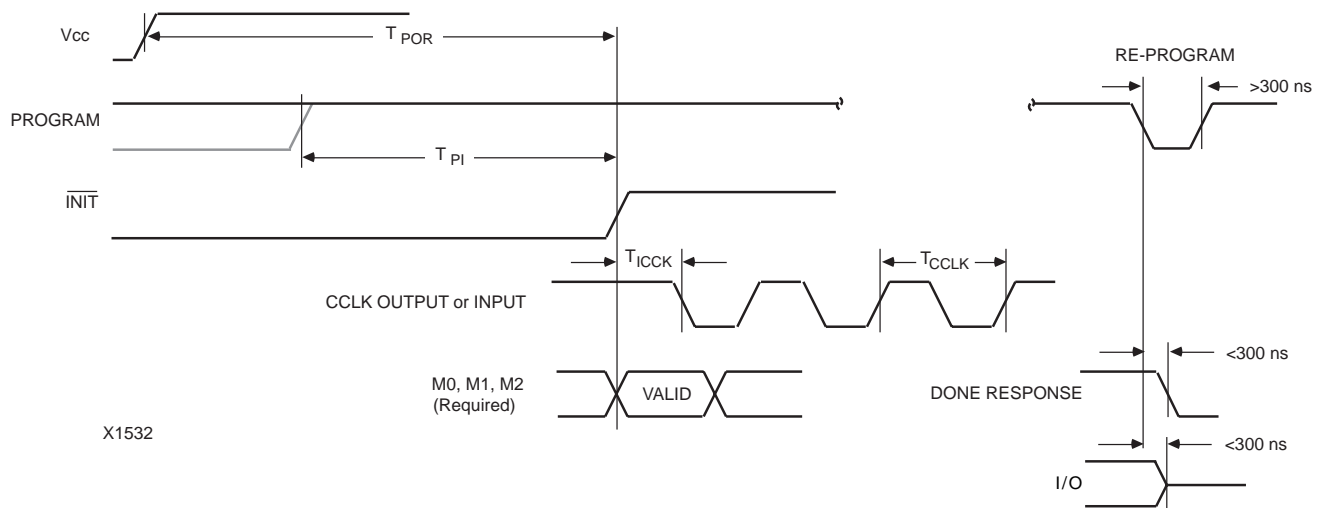


	Description	Symbol		Min	Max	Units
CCLK	INIT (High) Setup time required	1	T_{IC}	5		μs
	DIN Setup time required	2	T_{DC}	30		ns
	DIN hold time required	3	T_{CD}	0		ns
	CCLK High time		T_{CCH}	30		ns
	CCLK Low time		T_{CCL}	30		ns
	CCLK frequency		F_{CC}		10	MHz

Note: If not driven by the preceding DOUT, CS1 must remain high until the device is fully configured.

Figure 38: Express Mode Programming Switching Characteristics

Configuration Switching Characteristics



Master Modes

Description	Symbol	Min	Max	Units
Power-On-Reset	T_{POR}	2	15	ms
Program Latency	T_{PI}	6	70	μ s per CLB column
CCLK (output) Delay	T_{ICCK}	40	375	μ s
period (slow)	T_{CCLK}	640	3000	ns
period (fast)	T_{CCLK}	100	375	ns

7

Slave and Peripheral Modes

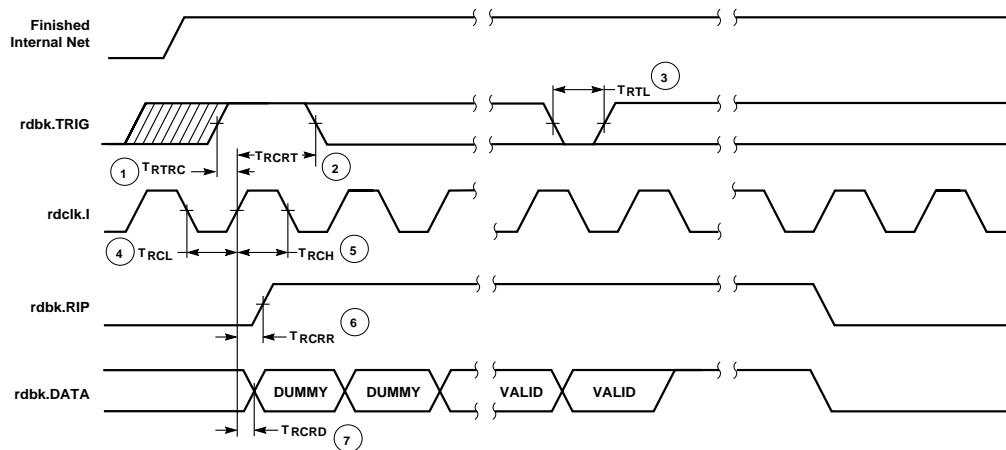
Description	Symbol	Min	Max	Units
Power-On-Reset	T_{POR}	2	15	ms
Program Latency	T_{PI}	6	70	μ s per CLB column
CCLK (input) Delay (required)	T_{ICCK}	5		μ s
period (required)	T_{CCLK}	100		ns

Note: At power-up, V_{CC} must rise from 2.0 to V_{CC} min in less than 15 ms, otherwise delay configuration using PROGRAM until V_{CC} is valid.

XC5200 Program Readback Switching Characteristic Guidelines

Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100% functionally tested. Internal timing parameters are not measured directly. They are derived from benchmark timing patterns that are taken at device introduction, prior to any process improvements.

The following guidelines reflect worst-case values over the recommended operating conditions.



X1790

	Description	Symbol	Min	Max	Units
rdbk.TRIG	rdbk.TRIG setup to initiate and abort Readback	1 T_{RTRC}	200	-	ns
	rdbk.TRIG hold to initiate and abort Readback	2 T_{RCRT}	50	-	ns
rdclk.1	rdbk.DATA delay	7 T_{RCRD}	-	250	ns
	rdbk.RIP delay	6 T_{RCRR}	-	250	ns
	High time	5 T_{RCH}	250	500	ns
	Low time	4 T_{RCL}	250	500	ns

Note 1: Timing parameters apply to all speed grades.

Note 2: rdbk.TRIG is High prior to Finished, Finished will trigger the first Readback

XC5200 Switching Characteristics

Definition of Terms

In the following tables, some specifications may be designated as Advance or Preliminary. These terms are defined as follows:

Advance: Initial estimates based on simulation and/or extrapolation from other speed grades, devices, or device families. Use as estimates, not for production.

Preliminary: Based on preliminary characterization. Further changes are not expected.

Unmarked: Specifications not identified as either Advance or Preliminary are to be considered Final.¹

XC5200 Operating Conditions

Symbol	Description	Min	Max	Units
V_{CC}	Supply voltage relative to GND Commercial: 0°C to 85°C junction	4.75	5.25	V
	Supply voltage relative to GND Industrial: -40°C to 100°C junction	4.5	5.5	V
V_{IHT}	High-level input voltage — TTL configuration	2.0	V_{CC}	V
V_{ILT}	Low-level input voltage — TTL configuration	0	0.8	V
V_{IHC}	High-level input voltage — CMOS configuration	70%	100%	V_{CC}
V_{ILC}	Low-level input voltage — CMOS configuration	0	20%	V_{CC}
T_{IN}	Input signal transition time		250	ns

XC5200 DC Characteristics Over Operating Conditions

Symbol	Description	Min	Max	Units
V_{OH}	High-level output voltage @ $I_{OH} = -8.0$ mA, V_{CC} min	3.86		V
V_{OL}	Low-level output voltage @ $I_{OL} = 8.0$ mA, V_{CC} max		0.4	V
I_{CCO}	Quiescent FPGA supply current (Note 1)		15	mA
I_{IL}	Leakage current	-10	+10	μA
C_{IN}	Input capacitance (sample tested)		15	pF
I_{RIN}	Pad pull-up (when selected) @ $V_{IN} = 0$ V (sample tested)	0.02	0.30	mA

Note: 1. With no output current loads, all package pins at V_{CC} or GND, either TTL or CMOS inputs, and the FPGA configured with a tie option.

XC5200 Absolute Maximum Ratings

Symbol	Description		Units
V_{CC}	Supply voltage relative to GND	-0.5 to +7.0	V
V_{IN}	Input voltage with respect to GND	-0.5 to $V_{CC} + 0.5$	V
V_{TS}	Voltage applied to 3-state output	-0.5 to $V_{CC} + 0.5$	V
T_{STG}	Storage temperature (ambient)	-65 to +150	°C
T_{SOL}	Maximum soldering temperature (10 s @ 1/16 in. = 1.5 mm)	+260	°C
T_J	Junction temperature in plastic packages	+125	°C
	Junction temperature in ceramic packages	+150	°C

Note: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.

1. Notwithstanding the definition of the above terms, all specifications are subject to change without notice.

XC5200 Guaranteed Input and Output Parameters (Pin-to-Pin)

All values listed below are tested directly, and guaranteed over the operating conditions. The same parameters can also be derived indirectly from the Global Buffer specifications. The delay calculator uses this indirect method, and may overestimate because of worst-case assumptions. When there is a discrepancy between these two methods, the values listed below should be used, and the derived values should be considered conservative overestimates.

		Speed Grade	-6	-5	-4	-3
Description	Symbol	Device	Max (ns)	Max (ns)	Max (ns)	Max (ns)
Global Clock to Output Pad (fast) 	T_{ICKOF} (Max)	XC5202	16.9	15.1	10.9	9.8
		XC5204	17.1	15.3	11.3	9.9
		XC5206	17.2	15.4	11.9	10.8
		XC5210	17.2	15.4	12.8	11.2
		XC5215	19.0	17.0	12.8	11.7
Global Clock to Output Pad (slew-limited) 	T_{ICKO} (Max)	XC5202	21.4	18.7	12.6	11.5
		XC5204	21.6	18.9	13.3	11.9
		XC5206	21.7	19.0	13.6	12.5
		XC5210	21.7	19.0	15.0	12.9
		XC5215	24.3	21.2	15.0	13.1
Input Set-up Time (no delay) to CLB Flip-Flop 	T_{PSUF} (Min)	XC5202	2.5	2.0	1.9	1.9
		XC5204	2.3	1.9	1.9	1.9
		XC5206	2.2	1.9	1.9	1.9
		XC5210	2.2	1.9	1.9	1.8
		XC5215	2.0	1.8	1.7	1.7
Input Hold Time (no delay) to CLB Flip-Flop 	T_{PHF} (Min)	XC5202	3.8	3.8	3.5	3.5
		XC5204	3.9	3.9	3.8	3.6
		XC5206	4.4	4.4	4.4	4.3
		XC5210	5.1	5.1	4.9	4.8
		XC5215	5.8	5.8	5.7	5.6
Input Set-up Time (with delay) to CLB Flip-Flop DI Input 	T_{PSU}	XC5202	7.3	6.6	6.6	6.6
		XC5204	7.3	6.6	6.6	6.6
		XC5206	7.2	6.5	6.4	6.3
		XC5210	7.2	6.5	6.0	6.0
		XC5215	6.8	5.7	5.7	5.7
Input Set-up Time (with delay) to CLB Flip-Flop F Input 	T_{PSUL} (Min)	XC5202	8.8	7.7	7.5	7.5
		XC5204	8.6	7.5	7.5	7.5
		XC5206	8.5	7.4	7.4	7.4
		XC5210	8.5	7.4	7.4	7.3
		XC5215	8.5	7.4	7.4	7.2
Input Hold Time (with delay) to CLB Flip-Flop 	T_{PH} (Min)	XC52xx	0	0	0	0

- Note:**
- These measurements assume that the CLB flip-flop uses a direct interconnect to or from the IOB. The INREG/ OUTREG properties, or XACT-Performance, can be used to assure that direct connects are used. t_{PSU} applies only to the CLB input DI that bypasses the look-up table, which only offers direct connects to IOBs on the left and right edges of the die. t_{PSUL} applies to the CLB inputs F that feed the look-up table, which offers direct connect to IOBs on all four edges, as do the CLB Q outputs.
 - When testing outputs (fast or slew-limited), half of the outputs on one side of the device are switching.

Product Obsolete or Under Obsolescence



XC5200 Series Field Programmable Gate Arrays

Pin	Description	VQ64*	PC84	PQ100	VQ100	TQ144	PG156	Boundary Scan Order
	CCLK	48	73	77	74	107	R2	-
	VCC	-	74	78	75	108	P3	-
74.	I/O (TDO)	49	75	79	76	109	T1	0
	GND	-	76	80	77	110	N3	-
75.	I/O (A0, \overline{WS})	50	77	81	78	111	R1	9
76.	GCK4 (A1, I/O)	51	78	82	79	112	P2	15
77.	I/O (A2, CS1)	52	79	83	80	115	P1	18
78.	I/O (A3)	-	80	84	81	116	N1	21
	GND	-	-	-	-	118	L3	-
79.	I/O (A4)	-	81	85	82	121	K3	27
80.	I/O (A5)	53	82	86	83	122	K2	30
81.	I/O	-	-	87	84	123	K1	33
82.	I/O	-	-	88	85	124	J1	39
83.	I/O (A6)	54	83	89	86	125	J2	42
84.	I/O (A7)	55	84	90	87	126	J3	45
	GND	56	1	91	88	127	H2	-

* VQ64 package supports Master Serial, Slave Serial, and Express configuration modes only.

Additional No Connect (N.C.) Connections on TQ144 Package

TQ144					
135	9	41	67	98	117
136	10	42	68	99	119
140	25	46	77	103	120
141	26	47	78	104	
4	30	62	82	113	
5	31	63	83	114	

Notes: Boundary Scan Bit 0 = TDO.T
Boundary Scan Bit 1 = TDO.O
Boundary Scan Bit 1056 = BSCAN.UPD

Pin Locations for XC5204 Devices

The following table may contain pinout information for unsupported device/package combinations. Please see the availability charts elsewhere in the XC5200 Series data sheet for availability information.

Pin	Description		PC84	PQ100	VQ100	TQ144	PG156	PQ160	Boundary Scan Order
	VCC		2	92	89	128	H3	142	-
1.	I/O (A8)		3	93	90	129	H1	143	78
2.	I/O (A9)		4	94	91	130	G1	144	81
3.	I/O		-	95	92	131	G2	145	87
4.	I/O		-	96	93	132	G3	146	90
5.	I/O (A10)		5	97	94	133	F1	147	93
6.	I/O (A11)		6	98	95	134	F2	148	99
7.	I/O		-	-	-	135	E1	149	102
8.	I/O		-	-	-	136	E2	150	105
	GND		-	-	-	137	F3	151	-
9.	I/O		-	-	-	-	D1	152	111
10.	I/O		-	-	-	-	D2	153	114
11.	I/O (A12)		7	99	96	138	E3	154	117
12.	I/O (A13)		8	100	97	139	C1	155	123
13.	I/O		-	-	-	140	C2	156	126

Product Obsolete or Under Obsolescence

XC5200 Series Field Programmable Gate Arrays



Pin	Description	PC84	PQ100	VQ100	TQ144	PQ160	TQ176	PG191	PQ208	Boundary Scan Order
42.	I/O	-	-	-	-	-	28	C11	32	273
43.	I/O	25	19	16	23	25	29	B11	33	279
44.	I/O	26	20	17	24	26	30	A12	34	282
45.	I/O	-	-	-	25	27	31	B12	35	285
46.	I/O	-	-	-	26	28	32	A13	36	291
	GND	-	-	-	27	29	33	C12	37	-
47.	I/O	-	-	-	-	30	34	A15	40	294
48.	I/O	-	-	-	-	31	35	C13	41	297
49.	I/O	27	21	18	28	32	36	B14	42	303
50.	I/O	-	22	19	29	33	37	A16	43	306
51.	I/O	-	-	-	30	34	38	B15	44	309
52.	I/O	-	-	-	31	35	39	C14	45	315
53.	I/O	28	23	20	32	36	40	A17	46	318
54.	I/O	29	24	21	33	37	41	B16	47	321
55.	M1 (I/O)	30	25	22	34	38	42	C15	48	330
	GND	31	26	23	35	39	43	D15	49	-
56.	M0 (I/O)	32	27	24	36	40	44	A18	50	333
	VCC	33	28	25	37	41	45	D16	55	-
57.	M2 (I/O)	34	29	26	38	42	46	C16	56	336
58.	GCK2 (I/O)	35	30	27	39	43	47	B17	57	339
59.	I/O (HDC)	36	31	28	40	44	48	E16	58	348
60.	I/O	-	-	-	41	45	49	C17	59	351
61.	I/O	-	-	-	42	46	50	D17	60	354
62.	I/O	-	32	29	43	47	51	B18	61	360
63.	I/O (LDC)	37	33	30	44	48	52	E17	62	363
64.	I/O	-	-	-	-	49	53	F16	63	372
65.	I/O	-	-	-	-	50	54	C18	64	375
	GND	-	-	-	45	51	55	G16	67	-
66.	I/O	-	-	-	46	52	56	E18	68	378
67.	I/O	-	-	-	47	53	57	F18	69	384
68.	I/O	38	34	31	48	54	58	G17	70	387
69.	I/O	39	35	32	49	55	59	G18	71	390
70.	I/O	-	-	-	-	-	60	H16	72	396
71.	I/O	-	-	-	-	-	61	H17	73	399
72.	I/O	-	36	33	50	56	62	H18	74	402
73.	I/O	-	37	34	51	57	63	J18	75	408
74.	I/O	40	38	35	52	58	64	J17	76	411
75.	I/O (ERR, INIT)	41	39	36	53	59	65	J16	77	414
	VCC	42	40	37	54	60	66	J15	78	-
	GND	43	41	38	55	61	67	K15	79	-
76.	I/O	44	42	39	56	62	68	K16	80	420
77.	I/O	45	43	40	57	63	69	K17	81	423
78.	I/O	-	44	41	58	64	70	K18	82	426
79.	I/O	-	45	42	59	65	71	L18	83	432
80.	I/O	-	-	-	-	-	72	L17	84	435
81.	I/O	-	-	-	-	-	73	L16	85	438
82.	I/O	46	46	43	60	66	74	M18	86	444
83.	I/O	47	47	44	61	67	75	M17	87	447
84.	I/O	-	-	-	62	68	76	N18	88	450
85.	I/O	-	-	-	63	69	77	P18	89	456
	GND	-	-	-	64	70	78	M16	90	-
86.	I/O	-	-	-	-	71	79	T18	93	459

Product Obsolete or Under Obsolescence



XC5200 Series Field Programmable Gate Arrays

Pin	Description	PC84	TQ144	PQ160	TQ176	PQ208	PG223	BG225	PQ240	Boundary Scan Order
95.	I/O	-	-	-	-	-	H15	P7	85	519
96.	I/O	-	50	56	62	74	H18	R7	86	522
97.	I/O	-	51	57	63	75	J18	L7	87	528
98.	I/O	40	52	58	64	76	J17	N8	88	531
99.	I/O (ERR, INIT)	41	53	59	65	77	J16	P8	89	534
	VCC	42	54	60	66	78	J15	VCC*	90	-
	GND	43	55	61	67	79	K15	GND*	91	-
100.	I/O	44	56	62	68	80	K16	L8	92	540
101.	I/O	45	57	63	69	81	K17	P9	93	543
102.	I/O	-	58	64	70	82	K18	R9	94	546
103.	I/O	-	59	65	71	83	L18	N9	95	552
104.	I/O	-	-	-	72	84	L17	M9	96	555
105.	I/O	-	-	-	73	85	L16	L9	97	558
106.	I/O	-	-	-	-	-	L15	R10	99	564
107.	I/O	-	-	-	-	-	M15	P10	100	567
	VCC	-	-	-	-	-	-	VCC*	101	-
108.	I/O	46	60	66	74	86	M18	N10	102	570
109.	I/O	47	61	67	75	87	M17	K9	103	576
110.	I/O	-	62	68	76	88	N18	R11	104	579
111.	I/O	-	63	69	77	89	P18	P11	105	588
	GND	-	64	70	78	90	M16	GND*	106	-
112.	I/O	-	-	-	-	-	N15	M10	107	591
113.	I/O	-	-	-	-	-	P15	N11	108	600
114.	I/O	-	-	-	-	91	N17	R12	109	603
115.	I/O	-	-	-	-	92	R18	L10	110	606
116.	I/O	-	-	71	79	93	T18	P12	111	612
117.	I/O	-	-	72	80	94	P17	M11	112	615
118.	I/O	48	65	73	81	95	N16	R13	113	618
119.	I/O	49	66	74	82	96	T17	N12	114	624
120.	I/O	-	67	75	83	97	R17	P13	115	627
121.	I/O	-	68	76	84	98	P16	K10	116	630
122.	I/O	50	69	77	85	99	U18	R14	117	636
123.	I/O	51	70	78	86	100	T16	N13	118	639
	GND	52	71	79	87	101	R16	GND*	119	-
	DONE	53	72	80	88	103	U17	P14	120	-
	VCC	54	73	81	89	106	R15	VCC*	121	-
	PROG	55	74	82	90	108	V18	M12	122	-
124.	I/O (D7)	56	75	83	91	109	T15	P15	123	648
125.	GCK3 (I/O)	57	76	84	92	110	U16	N14	124	651
126.	I/O	-	77	85	93	111	T14	L11	125	660
127.	I/O	-	78	86	94	112	U15	M13	126	663
128.	I/O	-	-	-	-	-	R14	N15	127	666
129.	I/O	-	-	-	-	-	R13	M14	128	672
130.	I/O (D6)	58	79	87	95	113	V17	J10	129	675
131.	I/O	-	80	88	96	114	V16	L12	130	678
132.	I/O	-	-	89	97	115	T13	M15	131	684
133.	I/O	-	-	90	98	116	U14	L13	132	687
134.	I/O	-	-	-	-	117	V15	L14	133	690
135.	I/O	-	-	-	-	118	V14	K11	134	696
	GND	-	81	91	99	119	T12	GND*	135	-
136.	I/O	-	-	-	-	-	R12	L15	136	699

Product Obsolete or Under Obsolescence



XC5200 Series Field Programmable Gate Arrays

Pin	Description	PQ160	HQ208	HQ240	PG299	BG225	BG352	Boundary Scan Order
235.	I/O	-	-	-	M5	-	B11	90
236.	I/O	-	-	-	P1	-	A11	93
237.	I/O (A4)	134	174	202	N1	A10	D12	99
238.	I/O (A5)	135	175	203	M3	D9	C12	102
239.	I/O	-	176	205	M2	C9	B12	105
240.	I/O	136	177	206	L5	B9	A12	111
241.	I/O	137	178	207	M1	A9	C13	114
242.	I/O	138	179	208	L4	E9	B13	117
243.	I/O (A6)	139	180	209	L3	C8	A13	126
244.	I/O (A7)	140	181	210	L2	B8	B14	129
	GND	141	182	211	L1	GND*	GND*	-

Additional No Connect (N.C.) Connections for HQ208 and HQ240 Packages

HQ208		HQ240
206	102	219
207	104	22
208	105	37
1	107	83
3	155	98
51	156	143
52	157	158
53	158	204
54	-	-

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Notes: * Pins labeled VCC* are internally bonded to a VCC plane within the BG225 and BG352 packages. The external pins for the BG225 are: B2, D8, H15, R8, B14, R1, H1, and R15. The external pins for the BG352 are: A10, A17, B2, B25, D13, D19, D7, G23, H4, K1, K26, N23, P4, U1, U26, W23, Y4, AC14, AC20, AC8, AE2, AE25, AF10, and AF17.
Pins labeled GND* are internally bonded to a ground plane within the BG225 and BG352 packages. The external pins for the BG225 are: A1, D12, G7, G9, H6, H8, H10, J8, K8, A8, F8, G8, H2, H7, H9, J7, J9, M8. The external pins for the BG352 are: A1, A2, A5, A8, A14, A19, A22, A25, A26, B1, B26, E1, E26, H1, H26, N1, P26, W1, W26, AB1, AB26, AE1, AE26, AF1, AF13, AF19, AF2, AF22, AF25, AF26, AF5, AF8.

Boundary Scan Bit 0 = TDO.T
Boundary Scan Bit 1 = TDO.O
Boundary Scan Bit 1056 = BSCAN.UPD

Product Obsolete or Under Obsolescence



XC5200 Series Field Programmable Gate Arrays

Revisions

Version	Description
12/97	Rev 5.0 added -3, -4 specification
7/98	Rev 5.1 added Spartan family to comparison, removed HQ304
11/98	Rev 5.2 All specifications made final.